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Australian Standard®

Surface chemical analysis—Secondary-ion mass spectrometry—Determination of relative sensitivity factors from ion-implanted reference materials

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This Standard was published on 20 October 2006.

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This Standard was issued in draft form for comment as DR 06502.

Standards Australia wishes to acknowledge the participation of the expert individuals that contributed to the development of this Standard through their representation on the Committee and through public comment period.

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First published as AS ISO 18114—2006.

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Published by Standards Australia, GPO Box 476, Sydney, NSW 2001, Australia

ISBN 0 7337 7782 1

PREFACE

This Standard was prepared by the Standards Australia Committee CH-016, Spectroscopy. This Standard is identical with, and has been reproduced from, ISO 18114:2003, *Surface chemical analysis—Secondary-ion mass spectrometry—Determination of relative sensitivity factors from ion-implanted reference materials*.

The objective of this Standard is to ensure that the method for determining relative sensitivity factors from ion-implanted reference materials is achieved.

As this Standard is reproduced from an International Standard, the following applies:

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Reference to International Standard ISO		*Australian Standard* AS ISO	
18115	Surface chemical analysis—Vocabulary	18115	Surface chemical analysis—Vocabulary

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INTRODUCTION

Ion-implanted materials are commonly used in secondary-ion mass spectrometry for the calibration of instruments. This international Standard was prepared to provide a uniform method for determining the relative sensitivity factor of an element in a specified matrix from an ion-implanted reference material, and to show how the concentration of the element in a different sample of the same matrix material can be determined.

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AUSTRALIAN STANDARD

Surface chemical analysis — Secondary-ion mass spectrometry — Determination of relative sensitivity factors from ion-implanted reference materials

1 Scope

This International Standard specifies a method of determining relative sensitivity factors (RSFs) for secondary-ion mass spectrometry (SIMS) from ion-implanted reference materials.

The method is applicable to specimens in which the matrix is of uniform chemical composition, and in which the peak concentration of the implanted species does not exceed one atomic percent.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 18115, *Surface chemical analysis — Vocabulary*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 18115 apply.

4 Symbols and abbreviated terms

Symbol	Description
$C_i^{A,M}$	the atomic concentration of the analyte element A in the matrix M at cycle i of a depth profile, expressed in atoms per unit volume
d	the depth over which the depth profile is integrated, expressed in length units
$I_i^{A_j}$	the detected count rates of the analyte ion of isotope A_j at measurement cycle i, expressed in counts/s
I_i^{M}	the detected count rates of the reference isotope M_k at measurement cycle i, expressed in counts/s
I_{BG}	the mean background count rate of species A_j, expressed in counts/s
N^{A_j}	the fractional isotopic abundance of the analyte isotope A_j in the unknown sample
n	the number of cycles over which the depth profile is integrated
Φ	the implanted fluence of isotope A_j, expressed in atoms per unit area
RSF	the relative sensitivity factor, expressed in atoms per unit volume
SIMS	secondary-ion mass spectrometry

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